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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Mandelis et al.  
Appl. No. : 10/797,607  
Filed : 3/11/2004  
Title : METHOD OF PHOTOCARRIER RADIOMETRY OF  
SEMICONDUCTORS  
Grp./A.U. : 2878  
Examiner :  
  
Docket No.: 14641

Honorable Assistant Commissioner of Patents  
Alexandria, VA 22313-1450

Sir:

**PTO CUSTOMER NO. 000293**

INFORMATION DISCLOSURE STATEMENT

In accordance with 37 C.F.R., §§ 1.97-1.99, applicant submits the following information which may be of interest to the examiner in charge of the above referenced application for patent. Copies of the references listed on the attached Form PTO-1449, List of Prior Art Cited by Applicant, are attached.

Respectfully submitted,

DOWELL & DOWELL, P. C.

Ralph A. Dowell, Reg. No.: 26,868

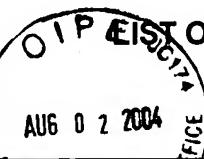
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Date: August 2, 2004

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FORM PTO-1449  
(Rev. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14641

Serial No.  
10/797,607O I P E LIST OF PRIOR ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT Mandelis et al.

FILING DATE March 11, 2004 GROUP 2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AD							
AE							
AF							

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AG		"Dynamics of the plasma and thermal waves in surface-modified semiconductors (invited)", Salnick et al., Rev. of Scientific Instruments, Vol. 74 (1), Jan. 2003, pgs. 545-549.
AH		"Non-contacting measurements of photocarrier lifetimes in bulk- and polycrystalline thin-film Si photoconductive devices by photothermal radiometry", Mandelis et al., J. Appl. Phys. Vol. 80 (9), Nov 1. 1996, pgs. 5332-5341.
AI		"Relative sensitivity of photomodulated reflectance and photothermal infrared radiometry to thermal and carrier plasma waves in semiconductors", Salnick et al., J. Appl. Phys. Vol. 82 (4), Aug 15, 1997, pgs. 1853-1859.
AJ		"Theoretical and experimental aspects of three-dimensional infrared photothermal radiometry of semiconductors", J. Appl. Phys. Vol 85 (10), Ikari et al., May 15, 1999, pgs. 7392-7397.
AK		"Minority carrier lifetime and iron concentration measurements on p-Si wafers by infrared photothermal radiometry and microwave photoconductance decay", Rodriguez et al., J. Appl. Phys. Vol 87 (11), June 1, 2000, pgs. 8113-8121.
AL		"Lock-in common-mode rejection demodulation: Measurement technique and applications to thermal-wave detection: Theoretical", Mandelis et al., Rev of Scientific Instruments Vol 71 (6), June 2000, pgs 2440-2444.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.